

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	2	("5404012") or ("6548810")).PN.	USPAT; USOCR	OR	OFF	2004/05/07 11:19
S2	0	energy near4 (cutoff cut-off) adj voltage same focus\$5 and "250"/\$.ccls. and image	USPAT; EPO; JPO; DERWENT	OR	ON	2004/05/07 10:59
S3	0	energy near4 (cutoff cut-off) adj voltage and "250"/\$.ccls. and image	USPAT; EPO; JPO; DERWENT	OR	ON	2004/05/07 10:59
S4	17	(cutoff cut-off) adj voltage and "250"/\$.ccls. and image	USPAT; EPO; JPO; DERWENT	OR	ON	2004/05/07 11:00
S5	7	((cutoff cut-off) adj voltage and "250"/\$.ccls. and image) and energy	USPAT; EPO; JPO; DERWENT	OR	ON	2004/05/07 11:02
S6	5	(((cutoff cut-off) adj voltage and "250"/\$.ccls. and image) and energy) and focus\$6	USPAT; EPO; JPO; DERWENT	OR	ON	2004/05/07 11:03
S7	675	"250"/\$.ccls. and focus\$5 and beam and filter and voltage with (wafer substrate sample specimen)	USPAT; EPO; JPO; DERWENT	OR	ON	2004/05/07 11:20
S8	501	("250"/\$.ccls. and focus\$5 and beam and filter and voltage with (wafer substrate sample specimen)) and intensit\$5	USPAT; EPO; JPO; DERWENT	OR	ON	2004/05/07 11:21
S9	430	((("250"/\$.ccls. and focus\$5 and beam and filter and voltage with (wafer substrate sample specimen)) and intensit\$5) and lens	USPAT; EPO; JPO; DERWENT	OR	ON	2004/05/07 11:21
S10	305	(((("250"/\$.ccls. and focus\$5 and beam and filter and voltage with (wafer substrate sample specimen)) and intensit\$5) and lens) and image	USPAT; EPO; JPO; DERWENT	OR	ON	2004/05/07 11:21
S11	144	((((("250"/\$.ccls. and focus\$5 and beam and filter and voltage with (wafer substrate sample specimen)) and intensit\$5) and lens) and image) and filter same voltage	USPAT; EPO; JPO; DERWENT	OR	ON	2004/05/07 11:21
S12	855	electron adj beam and imag\$6 and filter with voltage	USPAT; EPO; JPO; DERWENT	OR	ON	2005/01/27 10:16
S13	144	S12 and bias adj voltage	USPAT; EPO; JPO; DERWENT	OR	ON	2005/01/21 13:56
S14	62	S13 and voltage with (negative invers\$5)	USPAT; EPO; JPO; DERWENT	OR	ON	2005/01/21 14:00

S15	2	(("6232787") or ("6344750")).PN.	USPAT	OR	OFF	2005/01/21 14:00
S16	60	electron adj beam and imag\$6 and filter near4 voltage and bias adj voltage	USPAT; EPO; JPO; DERWENT	OR	ON	2005/01/27 10:17
S17	24	S16 and (bias adj voltage same (negative inver\$7))	USPAT; EPO; JPO; DERWENT	OR	ON	2005/01/27 13:55